

Title (en)

SYSTEM FOR PERFORMING FAST TESTING DURING FLASH REFERENCE CELL SETTING

Title (de)

SYSTEM ZUR DURCHFÜHRUNG VON SCHNELLTESTS WÄHREND DER EINSTELLUNG VON FLASH-REFERENZZELLEN

Title (fr)

SYSTEME POUR LA REALISATION D'ESSAI RAPIDE LORS DU REGLAGE DE CELLULES DE REFERENCE DE MEMOIRE FLASH

Publication

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Application

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Abstract (en)

[origin: WO2006071402A1] An embedded circuit (14) in a memory device (10) is used in place of an external test device to perform time-consuming tasks such as voltage verification during the setting of reference cells (20). An external test device (16) programs at least one reference cell (22) to a predetermined value. The embedded circuit uses the cell (22) programmed by the external device as a comparative reference to program additional reference cells (20).

IPC 8 full level

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CPC (source: EP)

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